



US00D557156S

(12) **United States Design Patent** (10) **Patent No.:** **US D557,156 S**
Kon (45) **Date of Patent:** **** Dec. 11, 2007**

(54) **MASS SPECTROMETER**

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(73) Assignee: **ULVAC, Inc.**, Kanagawa (JP)

(**) Term: **14 Years**

(21) Appl. No.: **29/256,930**

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(51) **LOC (8) Cl.** **10-04**

(52) **U.S. Cl.** **D10/81**

(58) **Field of Classification Search** D10/81;
D24/169, 232; 250/281, 282, 285, 287, 288,
250/290-292

See application file for complete search history.

(56) **References Cited**

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(57) **CLAIM**

The ornamental design for a mass spectrometer, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a mass spectrometer.

FIG. 2 is a perspective view thereof.

FIG. 3 is a front elevation view thereof.

FIG. 4 is a rear elevation view thereof.

FIG. 5 is a top plan view thereof.

FIG. 6 is a bottom plan view thereof.

FIG. 7 is a right side elevation view thereof; and,

FIG. 8 is a left side elevation view thereof.

The portion of the article shown in broken lines is for illustrative purpose only and forms no part of the claimed design.

1 Claim, 8 Drawing Sheets

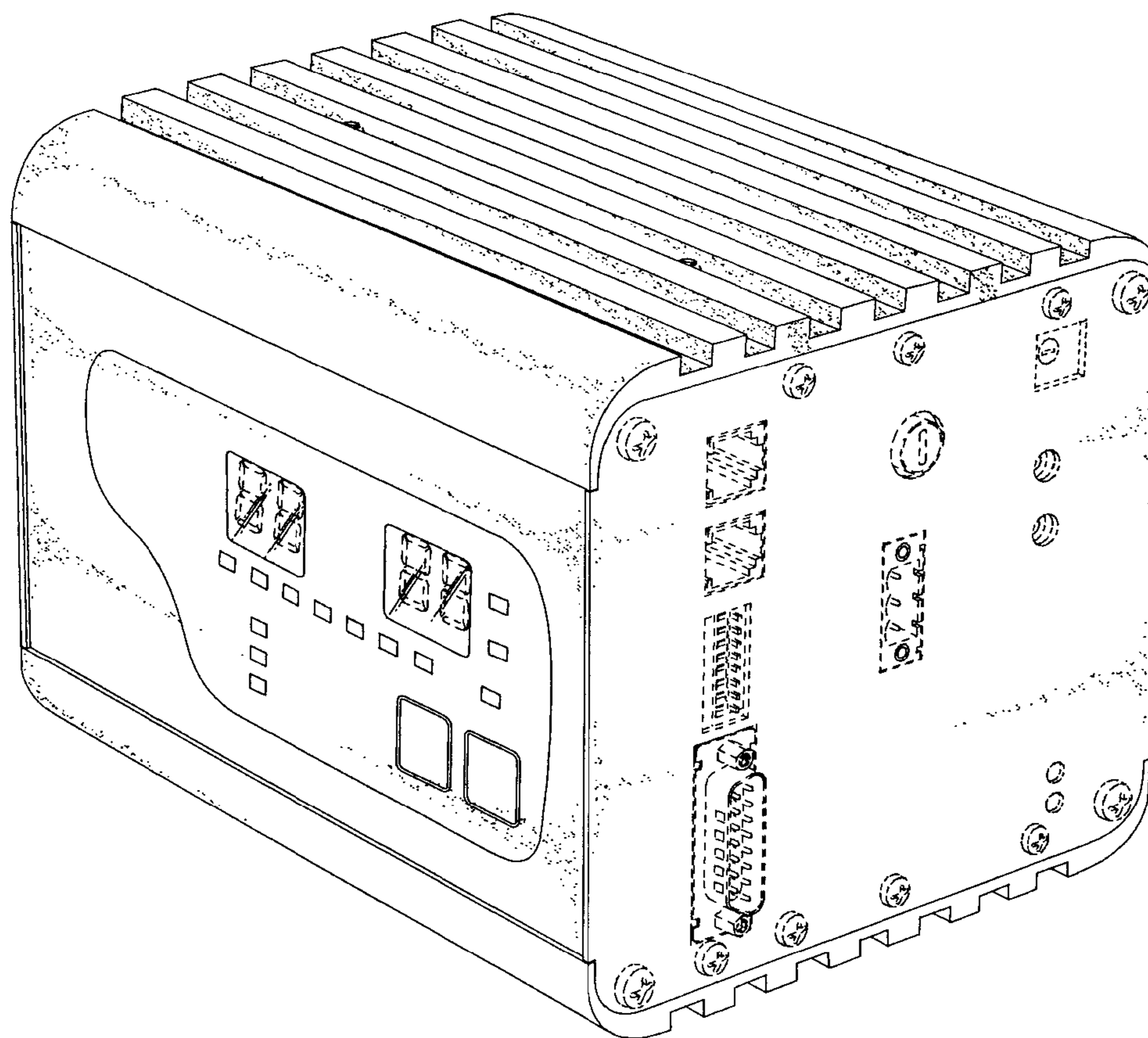


FIG. 1

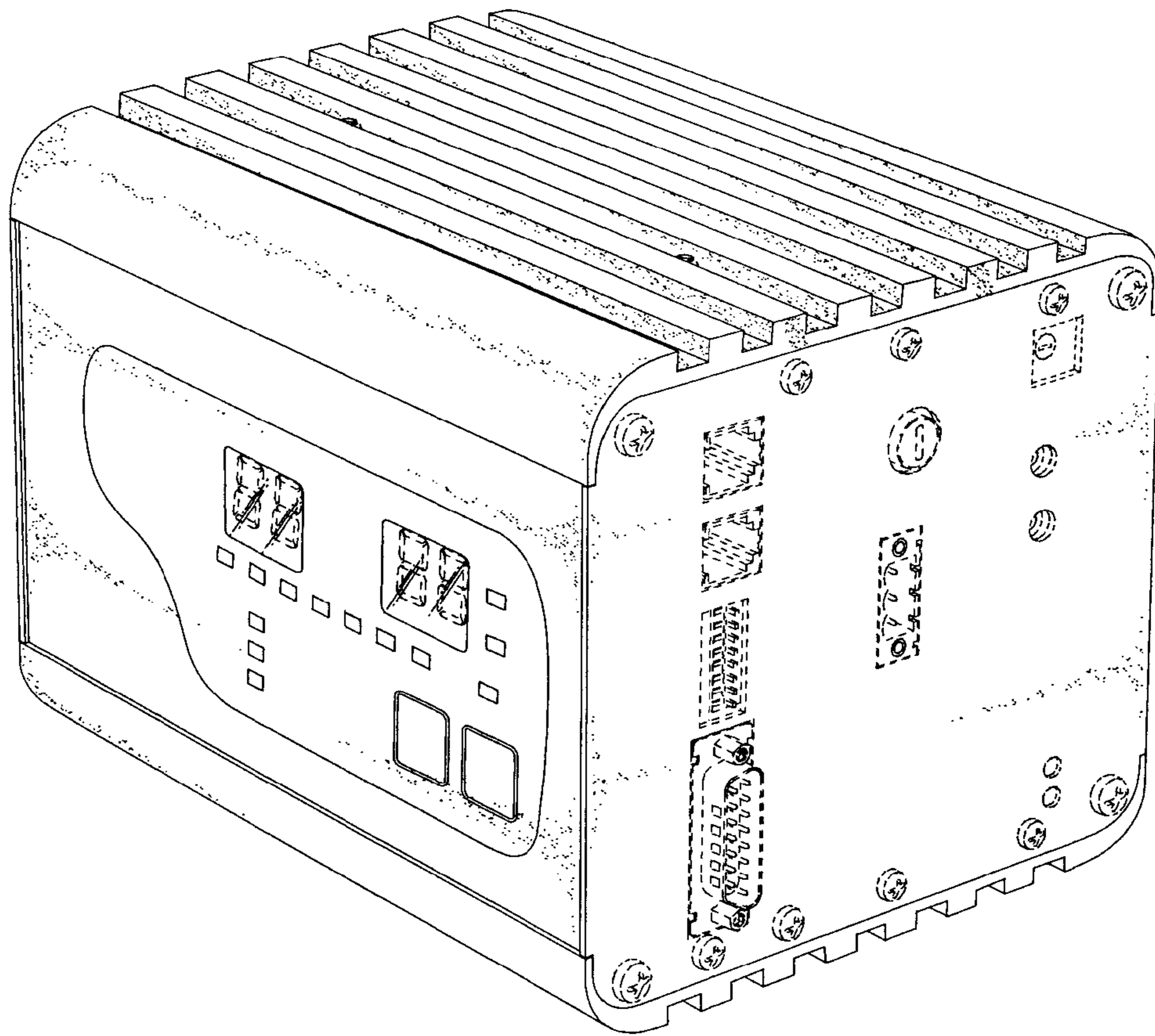


FIG. 2

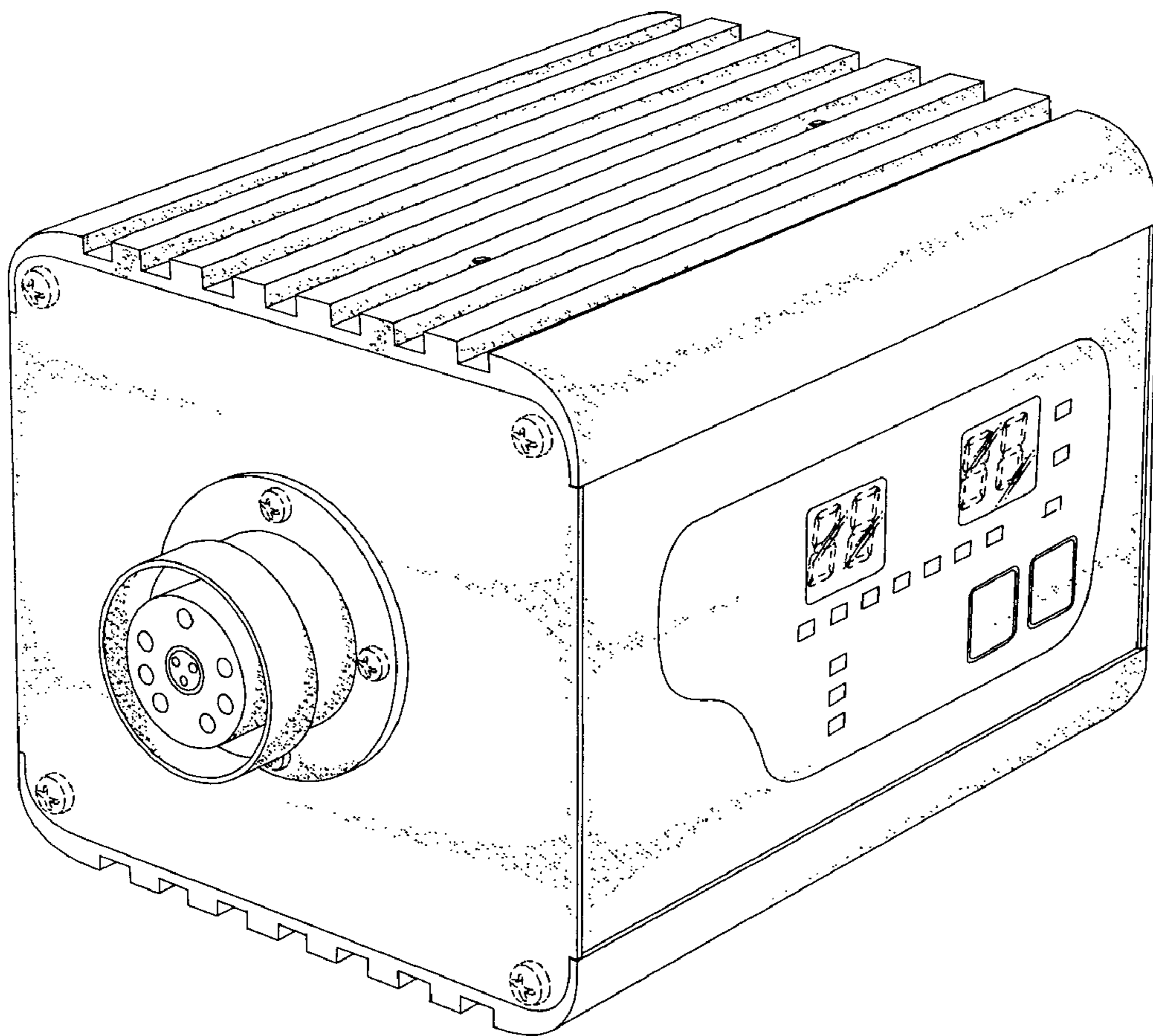


FIG. 3

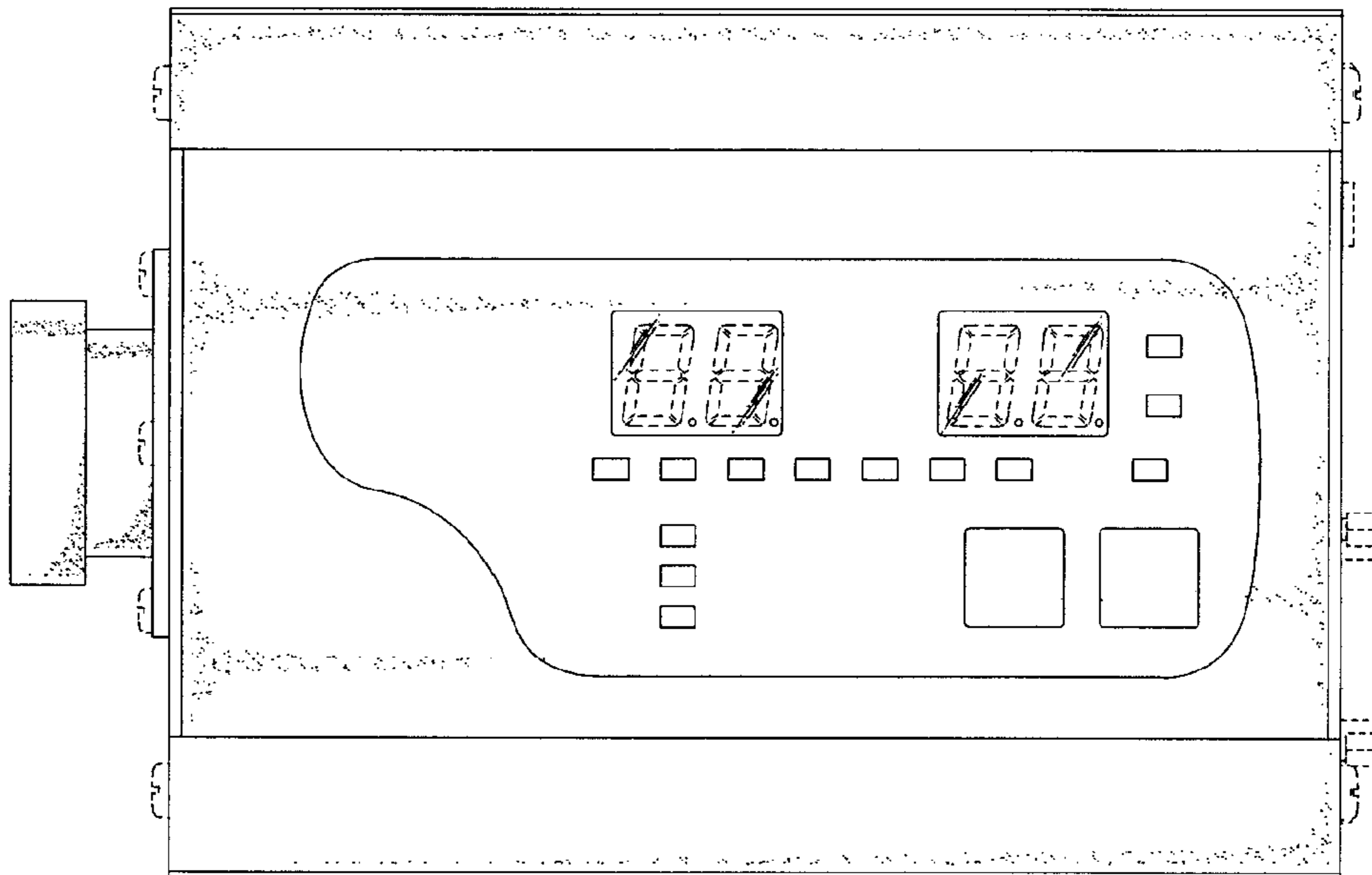


FIG. 4

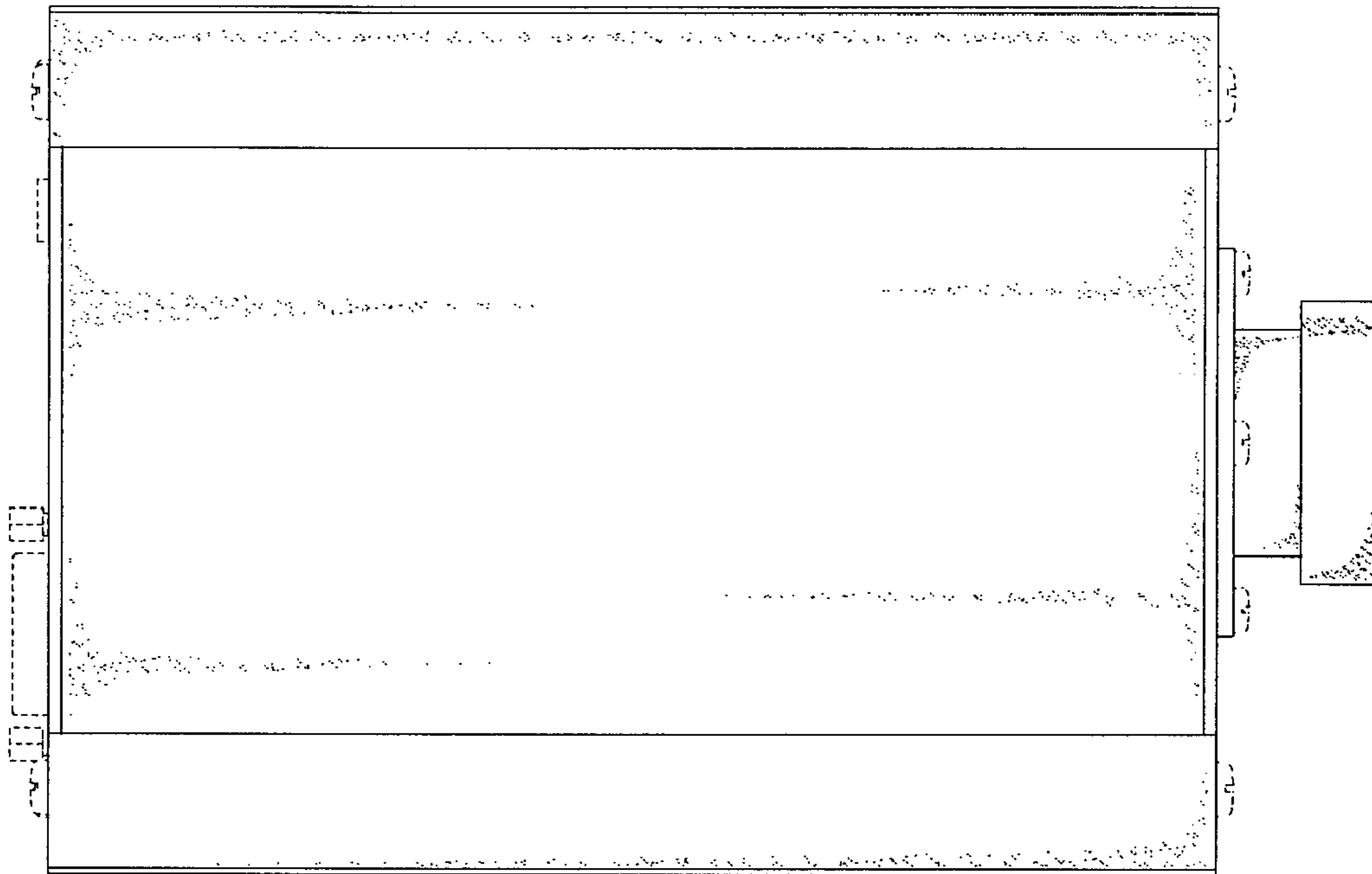


FIG. 5

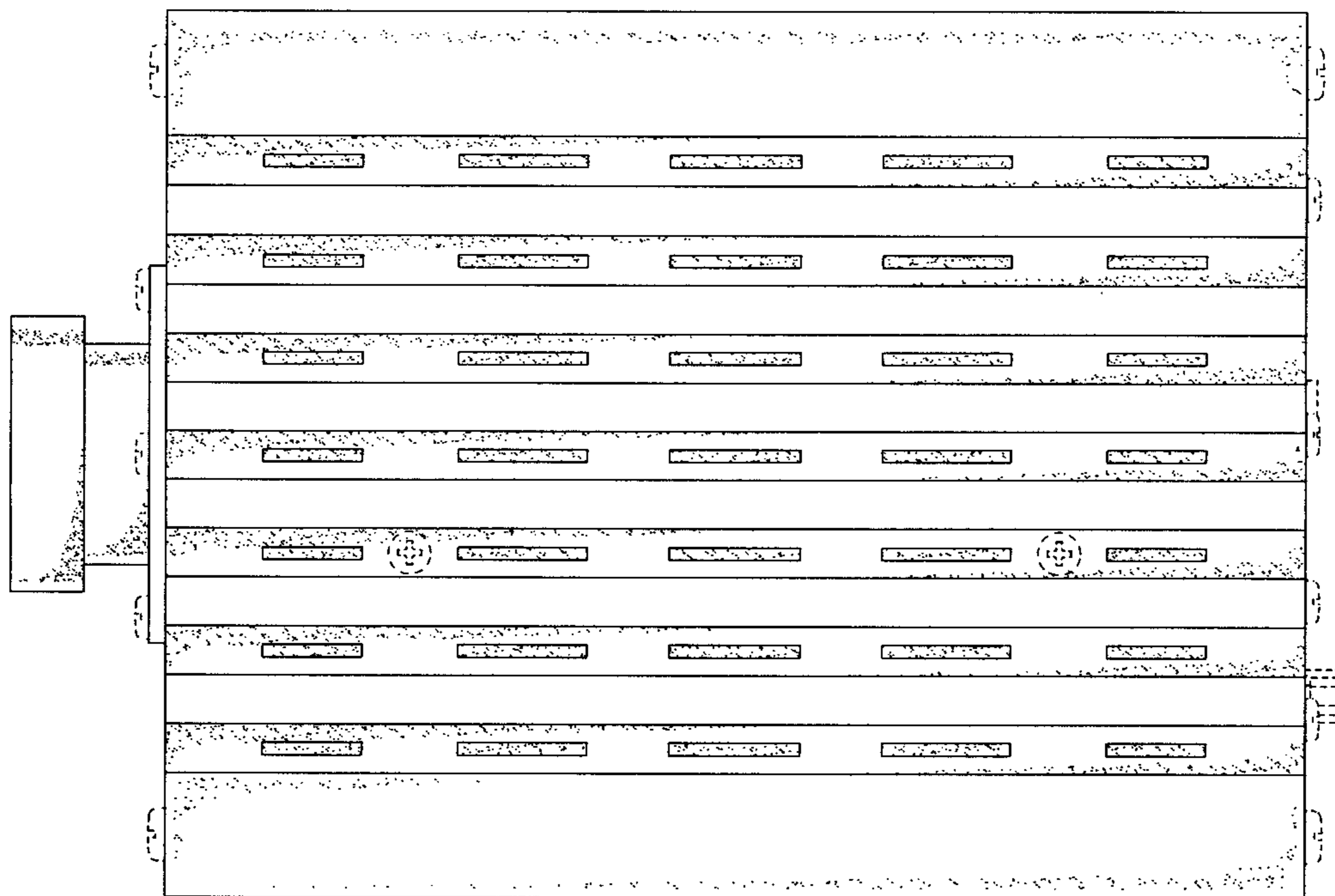


FIG. 7

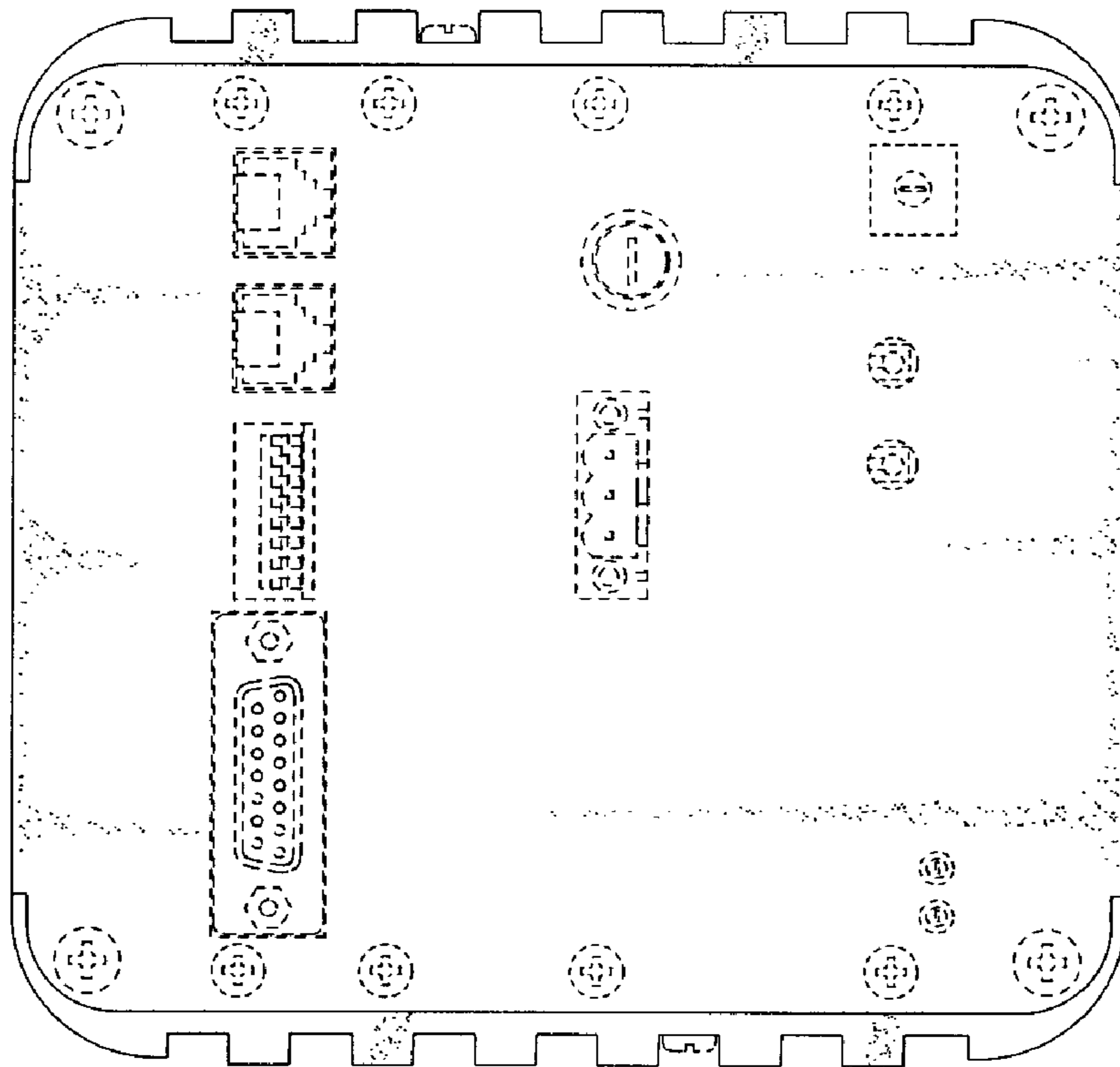


FIG. 8

